



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Ulrich Bonne et al. Confirmation No.:
Serial No.: 10/672,894 Examiner: unknown
Filing Date: September 26, 2003 Group Art: unknown
For: PHASED MICRO ANALYZER II, IIA
Docket No.: H0004785 (1100.1206101)

TRANSMITTAL SHEET

Assistant Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

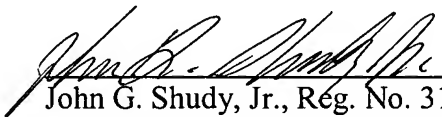
CERTIFICATE UNDER 37 C.F.R. 1.8: I hereby certify that this correspondence is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to the: Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450, on this 28th day of April, 2004.

By: 

John G. Shudy, Jr.

We are transmitting herewith the attached:

- ☒ Information Disclosure Statement, Form PTO-1449 listing 77 references and 45 non-US patent references attached.
- ☒ Please charge any deficiencies or credit any overpayment in the enclosed fees to Deposit Account No. 50-0413.


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INFORMATION DISCLOSURE STATEMENT (37 C.F.R. §1.97(b))

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By: 
John G. Shudy, Jr.

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner.

This statement should be considered because it is submitted before the mailing date of a first Office Action on-the-merits. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F. R. §1.98(a)(2), a copy of each non-US patent or other information listed on the enclosed Form 1449 is provided.

No representation is intended to be made hereby that any of the cited references establishes, by itself or in combination with other information, a prima facie case of unpatentability of any claim of the present case.

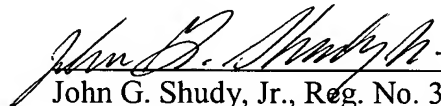
Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. 609, it is requested the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

Respectfully submitted,

Ulrich Bonne et al.

By his attorney,

Dated: 4-28-04



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10/672,894LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENT

Applicant: Ulrich Bonne et al.

Filing Date:
September 26, 2003Group Art:
unknown

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
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	3,783,356	01/1974	Lide, III et al.			
	4,043,196	08/1977	Trageser			
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	4,507,974	04/1985	Yelderman			
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	4,735,082	04/1988	Kolloff			
	4,759,210	07/1988	Wohltjen			
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		Filing Date: September 26, 2003	Group Art: unknown

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
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	6,393,894	05/2002	Bonne et al.			
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	DE 2 934 566 A1	03/19/81	Germany	Abstract
	DE 32 34 146 A1	03/15/84	Germany	Abstract
	DE 42 22 458 A1	01/13/94	Germany	Abstract
	DE 42 43 573 A1	06/23/94	Germany	Abstract
	DE 296 07 315 U1	09/26/96	Germany	Abstract
	EP 0 232 719 A1	01/10/87	Europe	Abstract
	EP 0 348 245 A2	12/27/89	Europe	
	EP 0 364 982 A2	04/25/90	Europe	
	EP 0 419 873 A2	08/29/90	Europe	
	EP 0 468 793 A2	01/29/92	Europe	
	EP 0 702 212 A2	03/20/96	Europe	
	EP 0 773 432 A2	05/14/97	Europe	Abstract
	GB 2 287 792 A	09/1995	United Kingdom	
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Examiner Initial	Document No.	Date	Country	Translation Yes No
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	Kindlund et al., "Quartz Crystal Gas Monitor With Gas Concentrating Stage," Sensors and Actuators, 6 (1984) pp.1-17.
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EXAMINER:	DATE CONSIDERED:
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.